

4.0A 800V N-CHANNEL POWER MOSFET

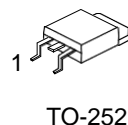
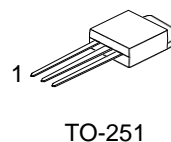
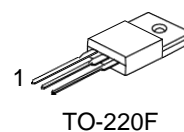
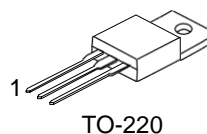
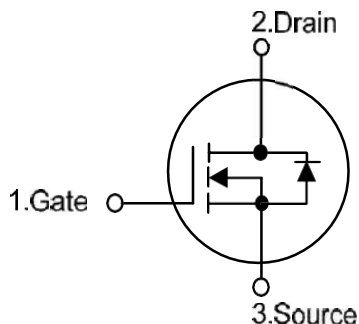
Description:

The KW4N80 is a N-channel mode power MOSFET using advanced technology to provide customers planar stripe and DMOS technology. This technology is specialized in allowing a minimum on-state resistance, and superior switching performance. It also can withstand high energy pulse in the avalanche and commutation mode.

Features:

- * $V_{DS} = 800V$
- * $I_D = 4.0A$
- * $R_{DS(ON)} = 3\Omega @ V_{GS} = 10V$.
- * High switching speed
- * Improved dv/dt capability
- * 100% avalanche tested

SYMBOL



ORDERING INFORMATION

Ordering Number	Package	Pin Assignment			Packing
		1	2	3	
KW4N80-LI	TO-220	G	D	S	Tape Box
KW4N80-BL	TO-220	G	D	S	Bulk
KW4N80F-LI	TO-220F	G	D	S	Tube
KW4N80A-LI	TO-251	G	D	S	Tube
KW4N80D-TR	TO-252	G	D	S	Tape Ree
KW4N80D-LI	TO-252	G	D	S	Tube

Note: Pin Assignment: G: Gate D: Drain S: Source

ABSOLUTE MAXIMUM RATINGS ($T_C=25^{\circ}\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	800	V
Gate-Source Voltage		V_{GSS}	± 30	V
Drain Current	Continuous	I_D	4.0	A
	Pulsed (Note 2)	I_{DM}	16	A
Avalanche Energy	Single Pulsed (Note 3)	E_{AS}	460	mJ
	Repetitive (Note 2)	E_{AR}	13	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	4.0	V/ns
Power Dissipation	TO-220	P_D	106	W
	TO-220F		36	W
	TO-251		50	W
	TO-252		50	W
Junction Temperature		T_J	+150	$^{\circ}\text{C}$
Storage Temperature		T_{STG}	-55~+150	$^{\circ}\text{C}$

Note: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature

3. $L=57\text{mH}$, $I_{AS}=4\text{A}$, $V_{DD}=50\text{V}$, $R_G=25\Omega$, Starting $T_J=25^{\circ}\text{C}$

4. $I_{SD}=4\text{A}$, $di/dt=200\text{A}/3\text{s}$, $V_{DD}=BV_{DSS}$, Starting $T_J=25^{\circ}\text{C}$

THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT
Junction to Ambient	TO-220	θ_{JA}	62.5	$^{\circ}\text{C}/\text{W}$
	TO-220F			
	TO-251			
	TO-252			
Junction to Case	TO-220	θ_{JC}	1.18	$^{\circ}\text{C}/\text{W}$
	TO-220F		3.47	$^{\circ}\text{C}/\text{W}$
	TO-251		2.5	$^{\circ}\text{C}/\text{W}$
	TO-252		2.5	$^{\circ}\text{C}/\text{W}$

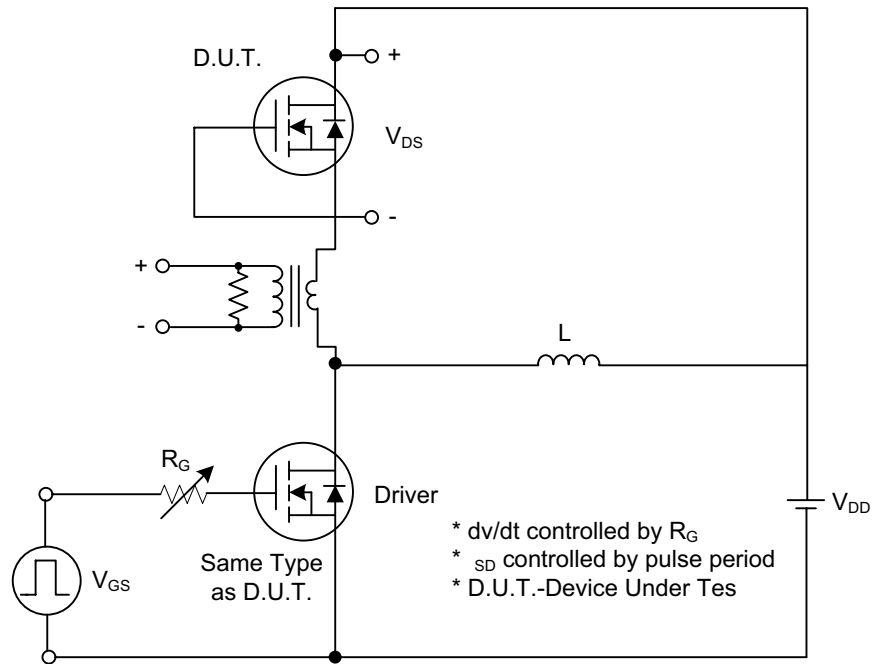
ELECTRICAL CHARACTERISTICS ($T_C=25^{\circ}\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	800			V
Breakdown Voltage Temperature Coefficient	$\frac{\Delta BV_{DSS}}{\Delta T_J}$	$I_D=250\mu A$, Referenced to 25°C		950		mV/ $^{\circ}\text{C}$
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=800V, V_{GS}=0V$			10	μA
		$V_{DS}=640V, T_C=125^{\circ}\text{C}$			100	μA
Gate-Source Leakage Current	Forward	$V_{DS}=0V, V_{GS}=30V$			100	nA
	Reverse	$V_{DS}=0V, V_{GS}=-30V$			-100	nA
ON CHARACTERISTICS						
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	3.0		5.0	V
Drain-Source On-State Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=2A$		2.3	3.0	Ω
DYNAMIC PARAMETERS						
Input Capacitance	C_{ISS}	$V_{DS}=25V, V_{GS}=0V, f=1.0\text{MHz}$		680	880	pF
Output Capacitance	C_{OSS}			75	100	pF
Reverse Transfer Capacitance	C_{RSS}			8.6	12	pF
SWITCHING PARAMETERS						
Total Gate Charge	Q_G	$V_{DS}=640V, V_{GS}=10V, I_D=4A$ (Note 1,2)		19	25	nC
Gate-Source Charge	Q_{GS}			4.2		nC
Gate-Drain Charge	Q_{GD}			9.1		nC
Turn-ON Delay Time	$t_{D(ON)}$	$V_{DD}=400V, I_D=4A, R_G=25\Omega$ (Note 1,2)		16	40	ns
Turn-ON Rise Time	t_R			45	100	ns
Turn-OFF Delay Time	$t_{D(OFF)}$			35	80	ns
Turn-OFF Fall Time	t_F			35	80	ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS						
Maximum Body-Diode Continuous Current	I_S				4	A
Maximum Body-Diode Pulsed Current	I_{SM}				16	A
Drain-Source Diode Forward Voltage	V_{SD}	$I_S=4A, V_{GS}=0V$			1.4	V
Body Diode Reverse Recovery Time	t_{rr}	$V_{GS}=0V, I_S=4A,$		575		ns
Body Diode Reverse Recovery Charge	Q_{RR}	$dI_F/dt=100A/\mu s$ (Note 1)		3.65		μC

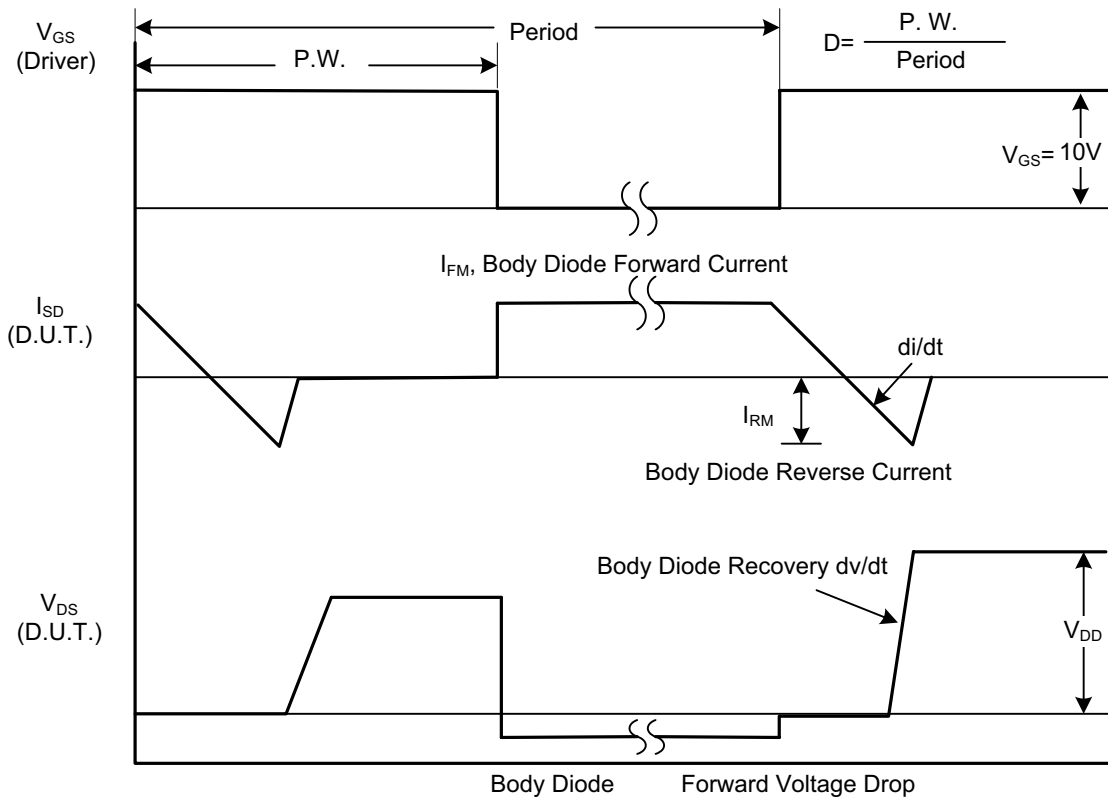
Note: 1. Pulse Test: Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$

2. Essentially independent of operating temperature

TEST CIRCUITS AND WAVEFORMS

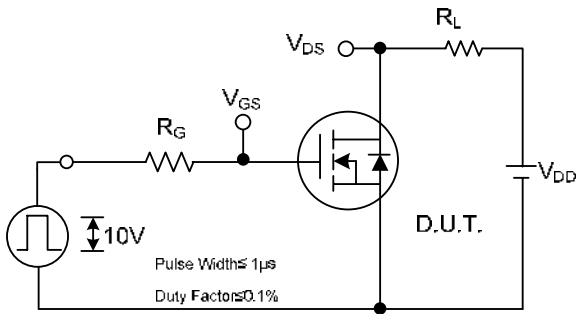


Peak Diode Recovery dv/dt Test Circuit

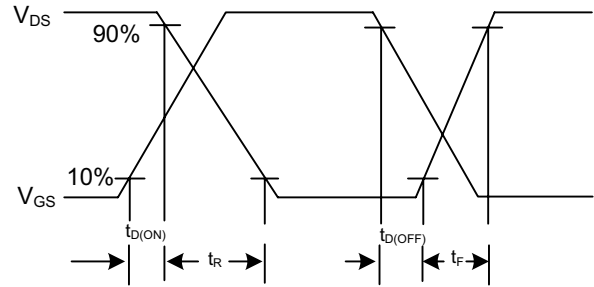


Peak Diode Recovery dv/dt Waveforms

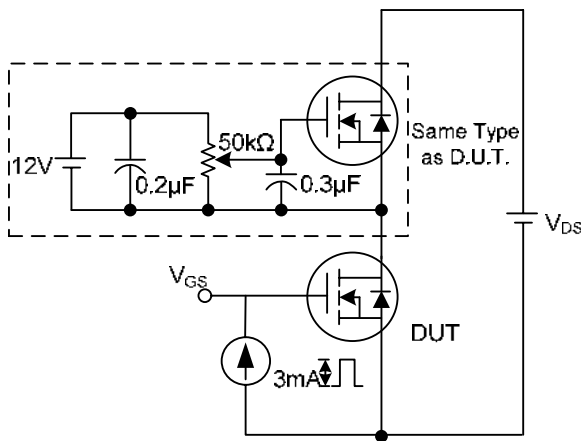
TEST CIRCUITS AND WAVEFORMS(Cont.)



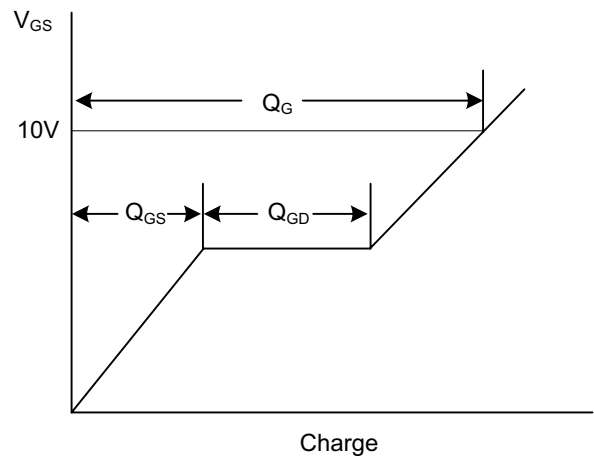
Switching Test Circuit



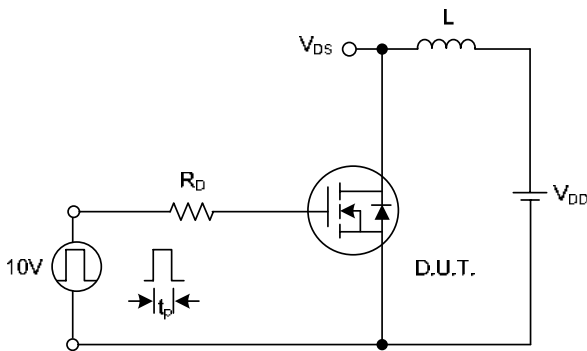
Switching Waveforms



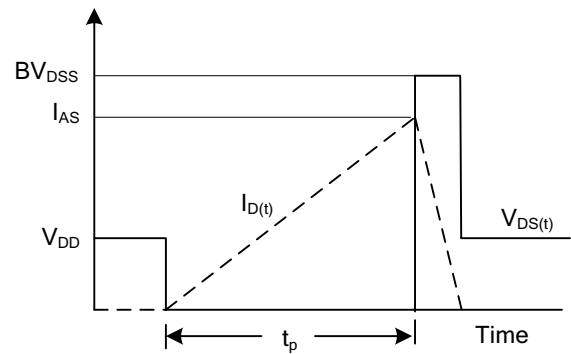
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

TYPICAL CHARACTERISTICS

